SCLS463A - JULY 2002 - REVISED JANUARY 2004

- Controlled Baseline
 - One Assembly/Test Site, One Fabrication Site
- Extended Temperature Performance of Up To -55°C to 125°C
- Enhanced Diminishing Manufacturing Sources (DMS) Support
- Enhanced Product-Change Notification
- Qualification Pedigree[†]
- 3-State Outputs Drive Bus Lines or Buffer Memory Address Registers
- High-Current Outputs Drive Up To 15 LSTTL Loads

DW OR PW PACKAGE (TOP VIEW)

		-		
10E [1	U	20	v _{cc}
1A1 [2		19	2 0E
2Y4 [3		18	1Y1
1A2 [4		17	2A4
2Y3 [5		16	1Y2
1A3 [6		15	2A3
2Y2 [7		14	1Y3
1A4 [8		13	2A2
2Y1 [9		12	1Y4
GND [10		11	2A1

description/ordering information

This octal buffer and line driver is designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters. The SN74HC244 is organized as two 4-bit buffers/drivers with separate output-enable (\overline{OE}) inputs. When \overline{OE} is low, the device passes noninverted data from the A inputs to the Y outputs. When \overline{OE} is high, the outputs are in the high-impedance state.

ORDERING INFORMATION

TA	PACKAGE‡		ORDERABLE PART NUMBER	TOP-SIDE MARKING
SOP - DW		Tape and reel	SN74HC244QDWREP	SHC244EP
-40°C to 125°C	TSSOP - PW	Tape and reel	SN74HC244QPWREP	SHC244EP
−55°C to 125°C	SOP – DW	Tape and reel	SN74HC244MDWREP	HC244MEP

[‡] Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

FUNCTION TABLE (each buffer/driver)

INPU	JTS	OUTPUT
OE	Α	Υ
L	Н	Н
L	L	L
Н	Χ	Z

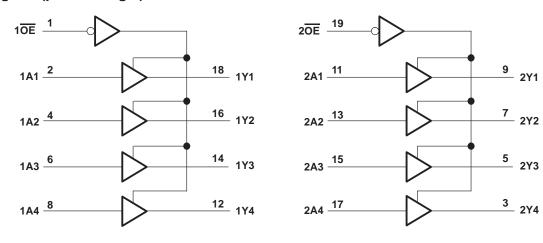


Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



[†] Component qualification in accordance with JEDEC and industry standards to ensure reliable operation over an extended temperature range. This includes, but is not limited to, Highly Accelerated Stress Test (HAST) or biased 85/85, temperature cycle, autoclave or unbiased HAST, electromigration, bond intermetallic life, and mold compound life.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range†

Supply voltage range, V _{CC}	–0.5 V to 7 V
Input clamp current, I _{IK} (V _I < 0 or V _I > V _{CC}) (see Note 1)	±20 mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC}) (see Note 1)	±20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±35 mA
Continuous current through V _{CC} or GND	±70 mA
Package thermal impedance, θ _{JA} (see Note 2): DW package	58°C/W
PW package	83°C/W
Storage temperature range, T _{stq}	65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51-7.

recommended operating conditions

			MIN	NOM	MAX	UNIT
VCC	Supply voltage		2	5	6	V
		V _{CC} = 2 V	1.5			
V_{IH}	High-level input voltage	$V_{CC} = 4.5 \text{ V}$	3.15			V
		V _{CC} = 6 V	4.2			
		V _{CC} = 2 V	0		0.5	
V_{IL}	/IL Low-level input voltage	V _{CC} = 4.5 V	0		1.35	V
		V _{CC} = 6 V	0		1.8	
٧ı	Input voltage		0		VCC	V
VO	Output voltage		0		VCC	V
		V _{CC} = 2 V	0		1000	
t _t	Input transition (rise and fall) time	V _{CC} = 4.5 V	0		500	ns
		V _{CC} = 6 V	0		400	
_		Q-suffix device	-40		125	00
T_A	Operating free-air temperature	M-suffix device	-55		125	°C



SN74HC244-EP **OCTAL BUFFER AND LINE DRIVER** WITH 3-STATE OUTPUTS SCLS463A – JULY 2002 – REVISED JANUARY 2004

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETER	TEST COMPLETE	2110	VCC	T	A = 25°C	;	BAINI	MAY	LINUT
PARAMETER	TEST CONDITIO	TEST CONDITIONS				MAX	MIN	MIN MAX	UNIT
			2 V	1.9	1.998		1.9		
		$I_{OH} = -20 \mu A$	4.5 V	4.4	4.499		4.4		
VOH	VI = VIH or VIL		6 V	5.9	5.999		5.9		V
		$I_{OH} = -6 \text{ mA}$	4.5 V	3.98	4.3		3.7		
		$I_{OH} = -7.8 \text{ mA}$	6 V	5.48	5.8		5.2		
			2 V		0.002	0.1		0.1	
	VI = VIH or VIL	l _{OL} = 20 μA	4.5 V		0.001	0.1		0.1	
VOL			6 V		0.001	0.1		0.1	V
		$I_{OL} = 6 \text{ mA}$	4.5 V		0.17	0.26		0.4	
		$I_{OL} = 7.8 \text{ mA}$	6 V		0.15	0.26		0.4	
lį	VI = VCC or 0		6 V		±0.1	±100		±1000	nA
loz	$V_O = V_{CC}$ or 0,	$V_I = V_{IH}$ or V_{IL}	6 V		±0.01	±0.5		±10	μΑ
ICC	$V_I = V_{CC}$ or 0,	IO = 0	6 V			8		160	μΑ
C _i			2 V to 6 V		3	10		10	pF

switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

DADAMETED	FROM	то	\ ,	TA	√ = 25°C	;		4 A V		
PARAMETER	(INPUT)	(OUTPUT)	vcc	MIN	TYP	MAX	MIN N	IAX	UNIT	
			2 V		40	115		170		
t _{pd}	А	Υ	4.5 V		13	23		34	ns	
·			6 V		11	20		29		
			2 V		75	150		225		
t _{en}	ŌĒ	Υ	4.5 V		15	30		45	ns	
			6 V		13	26		38		
			2 V		75	150		225		
^t dis	ŌĒ	Υ	4.5 V		15	30		45	ns	
			6 V		13	26		38		
			2 V		28	60		90		
tţ			Y	4.5 V		8	12		18	ns
			6 V		6	10		15		

SN74HC244-EP **OCTAL BUFFER AND LINE DRIVER** WITH 3-STATE OUTPUTS SCLS463A – JULY 2002 – REVISED JANUARY 2004

switching characteristics over recommended operating free-air temperature range, C_L = 150 pF (unless otherwise noted) (see Figure 1)

DADAMETED	FROM	то	.,	T _A = 25°C		AAINI AAAV	LINUT
PARAMETER	(INPUT)	(OUTPUT)	VCC	MIN TYP	MAX	MIN MAX	UNIT
			2 V	56	165	245	
t _{pd}	А	Υ	4.5 V	18	33	49	ns
·			6 V	15	28	42	
			2 V	100	200	300	
ten	ŌĒ	Υ	4.5 V	20	40	60	ns
			6 V	17	34	51	
			2 V	45	210	315	
t _t		Υ	4.5 V	17	42	63	ns
			6 V	13	36	53	

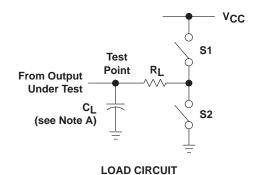
operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
Cpd	Power dissipation capacitance per buffer/driver	No load	35	pF

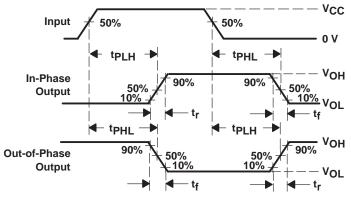


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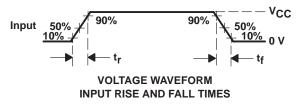
PARAMETER MEASUREMENT INFORMATION

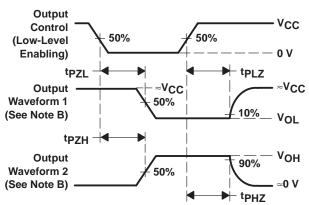


PARAI	PARAMETER		CL	S1	S2
	tPZH	1 k Ω	50 pF	Open	Closed
ten	tPZL			Closed	Open
4	tPHZ	1 kΩ	50 pF	Open	Closed
^t dis	tPLZ	1 K22	1 kΩ 50 pF		Open
t _{pd} or t _t		-	50 pF or 150 pF	Open	Open



VOLTAGE WAVEFORMS
PROPAGATION DELAY AND OUTPUT TRANSITION TIMES





VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES FOR 3-STATE OUTPUTS

- NOTES: A. C_L includes probe and test-fixture capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , t_f = 6 ns.
 - D. The outputs are measured one at a time with one input transition per measurement.
 - E. tpLz and tpHz are the same as tdis.
 - F. tpzL and tpzH are the same as ten.
 - G. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking
	(1)	(2)			(3)	(4)	(5)		(6)
SN74HC244MDWREP	Active	Production	SOIC (DW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC244MEP
SN74HC244MDWREP.A	Active	Production	SOIC (DW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC244MEP
SN74HC244QDWREP	Active	Production	SOIC (DW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	SHC244EP
SN74HC244QDWREP.A	Active	Production	SOIC (DW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	SHC244EP
SN74HC244QPWREP	Active	Production	TSSOP (PW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	SHC244EP
SN74HC244QPWREP.A	Active	Production	TSSOP (PW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	SHC244EP
SN74HC244QPWREPG4	Active	Production	TSSOP (PW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	SHC244EP
V62/03607-01XE	Active	Production	SOIC (DW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC244MEP
V62/03607-02XE	Active	Production	SOIC (DW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	SHC244EP
V62/03607-02YE	Active	Production	TSSOP (PW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	SHC244EP

⁽¹⁾ Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.



PACKAGE OPTION ADDENDUM

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and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF SN74HC244-EP:

Catalog: SN74HC244

Automotive: SN74HC244-Q1

Military: SN54HC244

NOTE: Qualified Version Definitions:

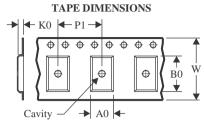
- Catalog TI's standard catalog product
- Automotive Q100 devices qualified for high-reliability automotive applications targeting zero defects
- Military QML certified for Military and Defense Applications

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

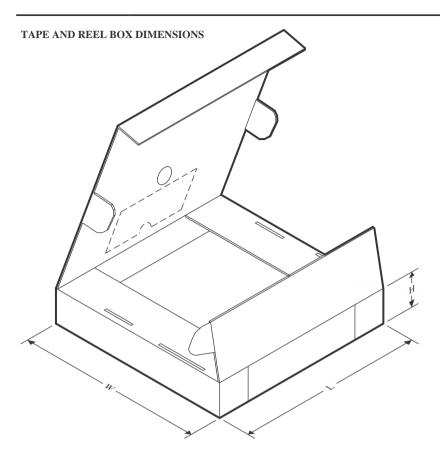
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74HC244MDWREP	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
SN74HC244QDWREP	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
SN74HC244QPWREP	TSSOP	PW	20	2000	330.0	16.4	6.95	7.0	1.4	8.0	16.0	Q1

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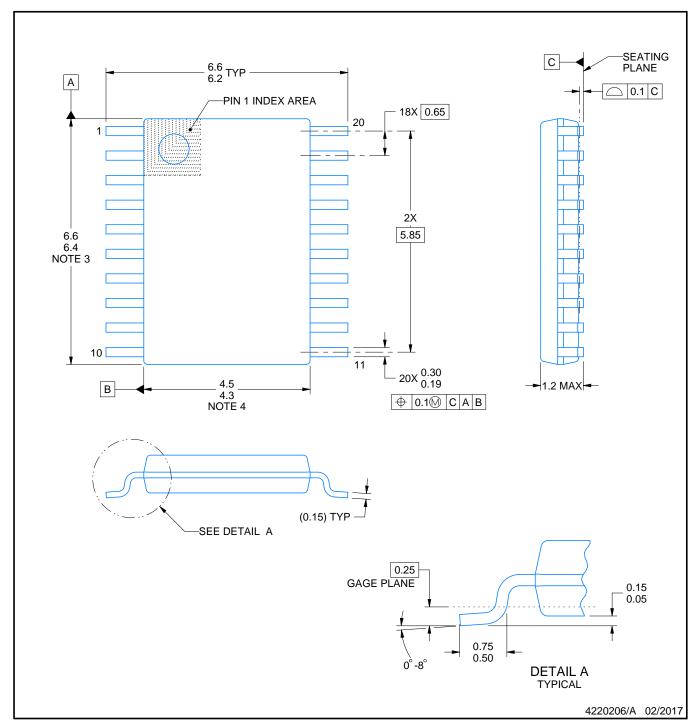


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74HC244MDWREP	SOIC	DW	20	2000	356.0	356.0	45.0
SN74HC244QDWREP	SOIC	DW	20	2000	356.0	356.0	45.0
SN74HC244QPWREP	TSSOP	PW	20	2000	353.0	353.0	32.0



SMALL OUTLINE PACKAGE



NOTES:

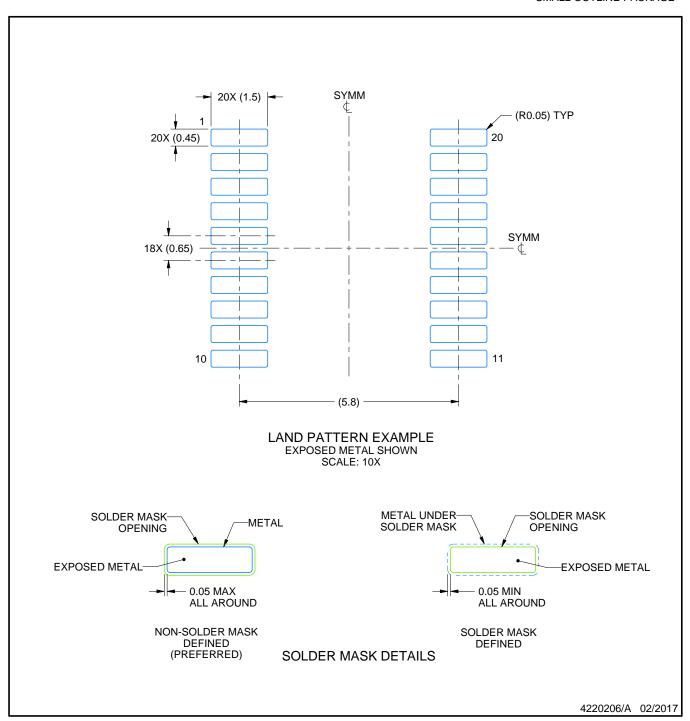
- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



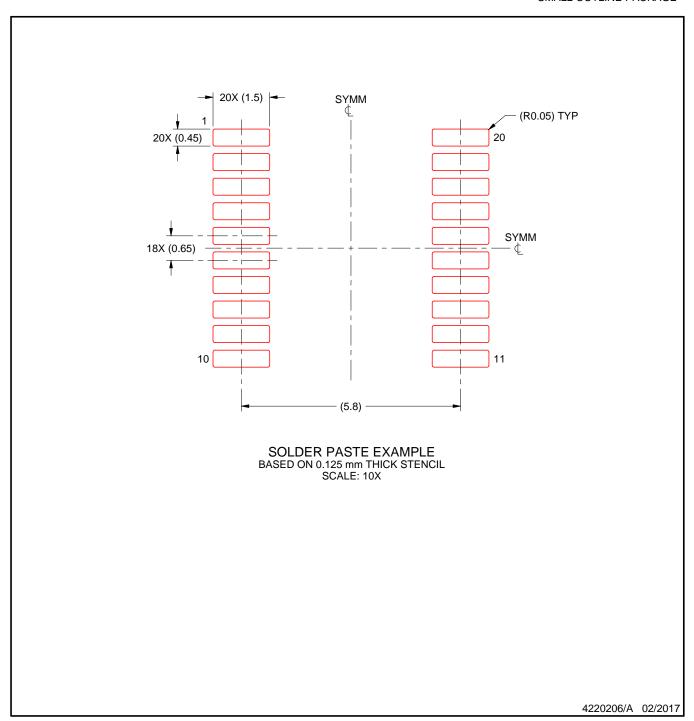
NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



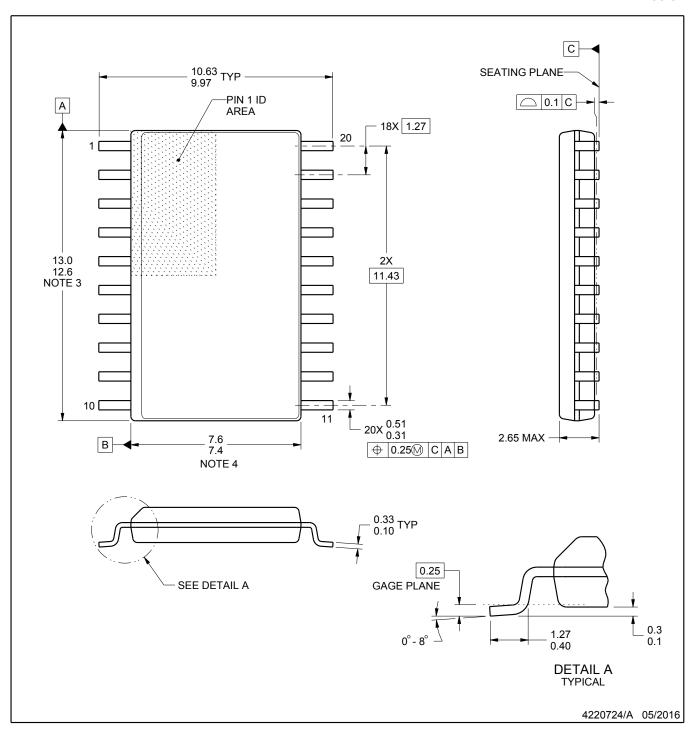
NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





SOIC



NOTES:

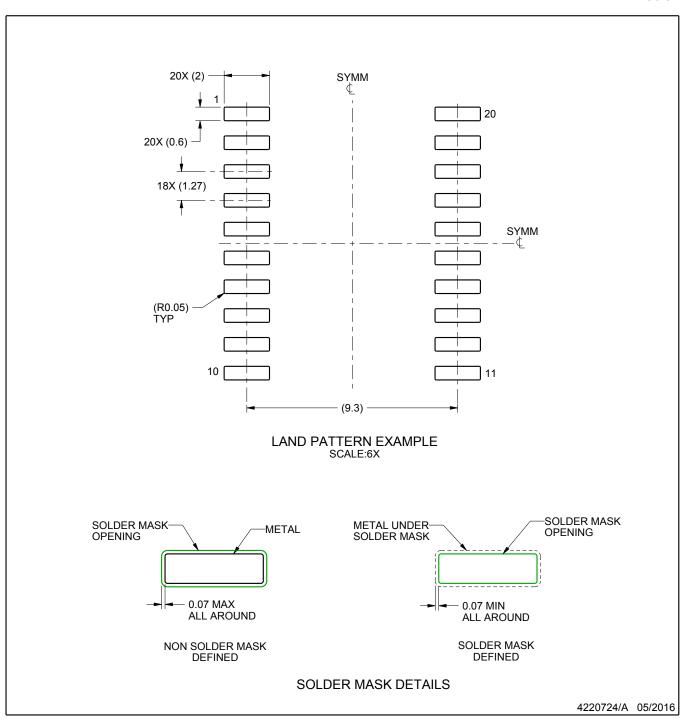
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- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
- 5. Reference JEDEC registration MS-013.



SOIC



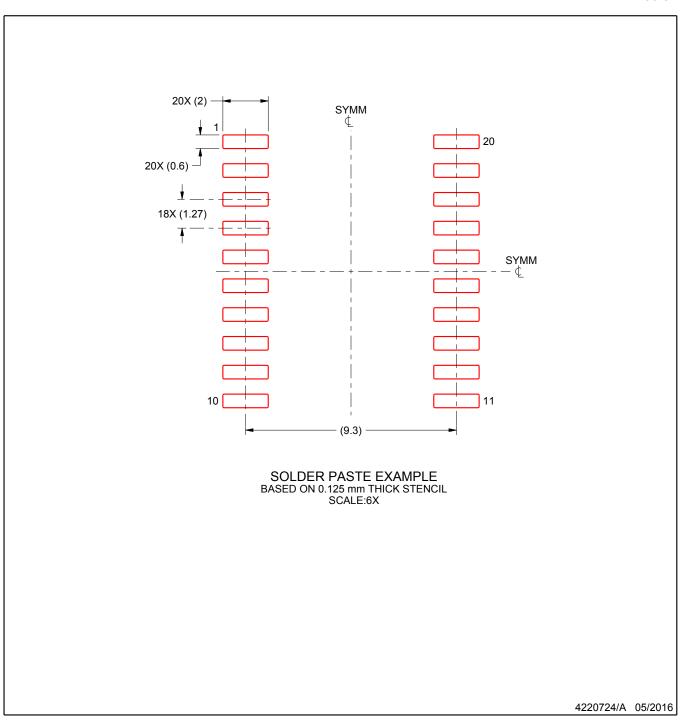
NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

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SOIC



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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